Search Note	S

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/563,184	DEPLAZES ET AL	
Examiner	Art Unit	
Eduardo Colon Santana	2837	

	SEARCHED		
Class	Subclass	Date	Examiner
187	248, 277 288, 391 393, 316	1/5/2007	ECS
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
SEARCH	ERENCE HISTORY ACHMENT	1/7/2007	ECS

SEARCH NOT (INCLUDING SEARCH !		
	DATE	EXMR
EAST SEARCH plus TEXT SEARCH INCLUDING EPO, JPO AND DERWERT DATATBASES	1/5/2007	ECS
TEXT SEARCH CLASS 187 AND 341 SEE ATTACHMENT	1/5/2007	ECS
TALK TO PRIMARY EXAMINER FOR FURTHER SEARCH AND/OR CLAIM INTERPRETATION	1/7/2007	ECS
PLUS SEARCH DONE BY 2800 EIC	1/7/2007	ECS